

## Drafts

## Pending

## Active

L1: (852) programmable SAME (analog\$ with blocks)

L2: (18672) switch\$ adj capacit\$

L3: (68) programmable SAME (analog\$ adj blocks)

L4: (85) 1 and 2

L5: (137) 3 or 4

## Failed

## Saved

## Favorites

## Tagged (4)

## UDC

## Queue

## Trash

Search

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DBs

USPAT, US-PGPUB, EPO, JPO, ☐ Plurals

Default operator: OR

☒ Highlight all hit terms initially

BRS form

ISR form

Image

Text

HTML

	U	1	Docume	Issue Dat	P	Title	Current	Current	R	Inventor
1	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 6311149 B1	20011030	27	Reconfigurable test system	703/21	703/23		Ryan, Arthur et al.
2	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5493246 A	19960220	8	Circuit and method of canceling leakage current in an analog	327/382	327/307; 327/378; 327/52;		Anderson, David J.
3	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 6590517 B1	20030708	51	Analog to digital conversion circuitry including backup co	341/155	341/139		Swanson, Eric J.
4	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 6614260 B1	20030902	12	System and method for dynamic modification of integ	326/41	326/10; 326/38		Welch, M. Jason et al.